



ELSEVIER

Computers in Industry 45 (2001) 319-320

COMPUTERS IN
INDUSTRY

www.elsevier.nl/locate/compind

Author index to volume 45

Alvi, M.I. , <i>see</i> Giachetti, R.E.	177
Bahr, B. , X. Xiao and K. Krishnan, A real-time scheme of cubic parametric curve interpolations for CNC systems	309
Barnard, J. , <i>see</i> Chambers, C.	277
Bee, G. , <i>see</i> Simon, M.	111
Bodner, D.A. , <i>see</i> Park, J.	79
Boykin, R.F. , Enterprise resource planning software: a solution to the return material authorization problem	99
Chambers, C. , M. Holcombe and J. Barnard, Introducing X-machine models to verify PLC ladder diagrams	277
Chan, A.H.S. , <i>see</i> Law, H.-W.	137
Chen, H.-N. , <i>see</i> Dabbas, R.M.	29
Cho, H. , <i>see</i> Park, S.	155
Chong, C.S. , <i>see</i> Sivakumar, A.I.	59
Chu, C. , <i>see</i> Wang, C.	215
Cochran, J.K. , and J.W. Fowler, Computers in the semiconductor industry	1
Dabbas, R.M. , and H.-N. Chen, Mining semiconductor manufacturing data for productivity improvement — an integrated relational database approach	29
Deng, J. , <i>see</i> Zhao, G.	261
Duffy, V.G. , <i>see</i> Kan, H.Y.	197
Eloranta, E. , A.-P. Hameri and M. Lahti, Improved project management through improved document management	231
Fowler, J.W. , <i>see</i> Cochran, J.K.	1
Giachetti, R.E. , and M.I. Alvi, An object-oriented information model for manufacturability analysis of printed circuit board fabrication	177
Hameri, A.-P. , <i>see</i> Eloranta, E.	231
Holcombe, M. , <i>see</i> Chambers, C.	277
Hui, I.K. , <i>see</i> Law, H.-W.	137
Joshi, M. , and S. Paiva, Web-based mining of statistical information	3
Kan, H.Y. , V.G. Duffy and C.-J. Su, An Internet virtual reality collaborative environment for effective product design	197
Kim, J.-H. , <i>see</i> Shin, Y.-H.	13
Krishnan, K. , <i>see</i> Bahr, B.	309
Lahti, M. , <i>see</i> Eloranta, E.	231

Law, H.-W., H.-Y. Tam, A.H.S. Chan and I.K. Hui, Object-oriented knowledge-based computer-aided process planning system for bare circuit boards manufacturing	137
Lee, H.-Y. , <i>see</i> Shin, Y.-H.	13
Lee, T.-E. , <i>see</i> Shin, Y.-H.	13
McGinnis, L.F. , <i>see</i> Park, J.	79
Moore, P. , <i>see</i> Simon, M.	111
Norrie, D.H. , <i>see</i> Xue, D.	245
Öztürk, F. , <i>see</i> Öztürk, N.	123
Öztürk, N. , and F. Öztürk, Neural network based non-standard feature recognition to integrate CAD and CAM	123
Paiva, S. , <i>see</i> Joshi, M.	3
Park, J., S.A. Reveliotis, D.A. Bodner, C. Zhou, J. Wu and L.F. McGinnis, High-fidelity rapid prototyping of 300 mm fabs through discrete event system modeling	79
Park, S., P. Yol Jang and H. Cho, Petri-net-based rapid development of a task execution module of equipment controller for distributed shop floor control	155
Pu, J.-S. , <i>see</i> Simon, M.	111
Reveliotis, S.A. , <i>see</i> Park, J.	79
Rivera, D.E. , <i>see</i> Vargas-Villamil, F.D.	45
Shen, W. , <i>see</i> Zhao, G.	261
Shin, Y.-H., T.-E. Lee, J.-H. Kim and H.-Y. Lee, Modeling and implementing a real-time scheduler for dual-armed cluster tools	13
Simon, M., G. Bee, P. Moore, J.-S. Pu and C. Xie, Modelling of the life cycle of products with data acquisition features	111
Sivakumar, A.I. , and C.S. Chong, A simulation based analysis of cycle time distribution, and throughput in semiconductor backend manufacturing	59
Son, Y.J. , and R.A. Wysk, Automatic simulation model generation for simulation-based, real-time shop floor control	291
Su, C.-J. , <i>see</i> Kan, H.Y.	197
Tam, H.-Y. , <i>see</i> Law, H.-W.	137
Vargas-Villamil, F.D. , and D.E. Rivera, A model predictive control approach for real-time optimization of reentrant manufacturing lines	45
Wang, C., C. Chu and C. Yin, Implementation of remote robot manufacturing over Internet	215
Wang, H. , <i>see</i> Xue, D.	245
Wu, J. , <i>see</i> Park, J.	79
Wysk, R.A. , <i>see</i> Son, Y.J.	291
Xiao, X. , <i>see</i> Bahr, B.	309
Xie, C. , <i>see</i> Simon, M.	111
Xue, D., H. Wang and D.H. Norrie, A fuzzy mathematics based optimal delivery scheduling approach	245
Yin, C. , <i>see</i> Wang, C.	215
Yol Jang, P. , <i>see</i> Park, S.	155
Zhao, G., J. Deng and W. Shen, CLOVER: an agent-based approach to systems interoperability in cooperative design systems	261
Zhou, C. , <i>see</i> Park, J.	79



ELSEVIER

Computers in Industry 45 (2001) 321-322

COMPUTERS IN
INDUSTRY

www.elsevier.nl/locate/compind

Subject index to volume 45

Appliances	111	Manufacturing modeling	177
Automatic generation	291	Model	13
Automation	3	Model predictive control	45
		Multi-agent systems	261
Business process engineering	231	Neural networks	123
CAD/CAM	123	New product development	231
Cluster tool	13		
CNC	309	Object-oriented systems	137
Colored Petri nets	79	One-of-a-kind industries	231
Computer Integrated Manufacturing (CIM)	29	Optimization	245
Computer-aided process planning	137		
Configuration management	215	98 Percentile cycle time	59
Cooperative engineering design	261	Performance reports	29
Cycle time distribution	59	Printed circuit board	177
		Product data management	231
Data acquisition	111	Product data model	215
Design for manufacturing	177	Product delivery	245
Discrete event system	45	Programmable logic controllers	277
Distributed objects	261		
Distributed shop floor control	155	Rapid development	155
		Rapid prototyping	79
Electronics manufacturing	137	Real-time optimization	45
ERP	99	Reentrant line	45
EXPRESS	177	Relational database	29
Extended Petri-net	155	Remote manufacturing	215
		Returned materials	99
Feature recognition	123	Reuse	111
Finite state machine	13		
Flexible automation	79	SAP R/3	99
Fluid approximation	45	SAS	3
Fuzzy-based clustering	245	Scheduling	13
		Semiconductor manufacturing	45, 59
High-fidelity modeling	79	Shop floor control	291
		Simulation	59, 291
Information integration	215	Simulation-based control	291
Information modeling	177	SPC	3
Information system	111	Spline interpolation	309
Intelligent scheduling	245	Standards	261
Interpolator	309	State-space search	245
		Systems interoperability	261
Knowledge-based systems	137		
Ladder diagram	277	Task execution module	155
Life cycle modelling	111	Testing	277
Lot release scheduling	59	The 300 mm fab	79
		Throughput	59

Virtual reality (VR)	197	Wafer fabrication	29
Virtual Reality Modeling Language (VRML)	197	Web Page	3
Virtual reality-based collaborative environment (VRCE)	197	X-machines	277